

# Design and Realization of an ALICE SDD End-Ladder Prototype

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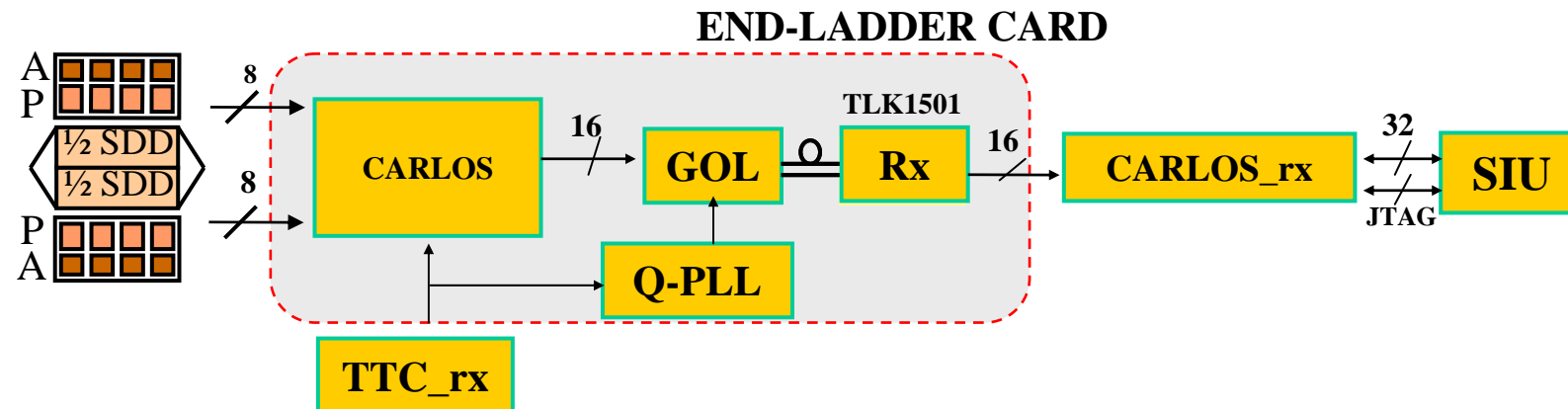
Physics Department University of Bologna



I.N.F.N. Sezione di Bologna



# The Full ALICE SDD Readout Chain



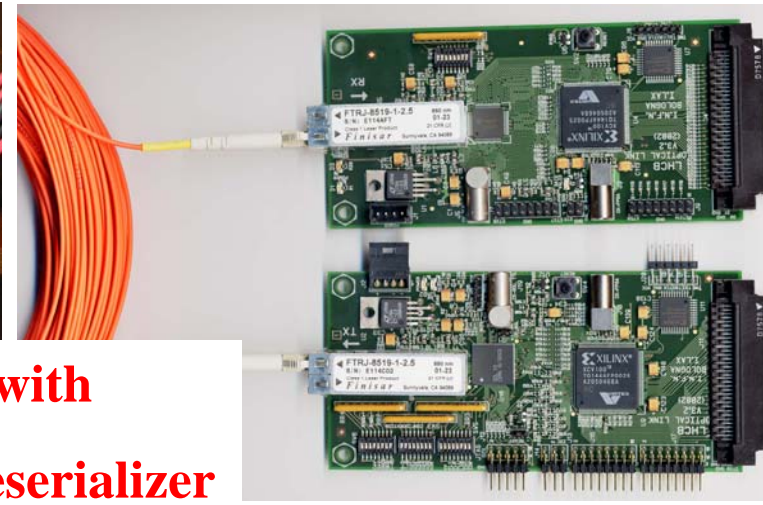
**Test of the chain performed first in Bologna and then at CERN (2-3)**



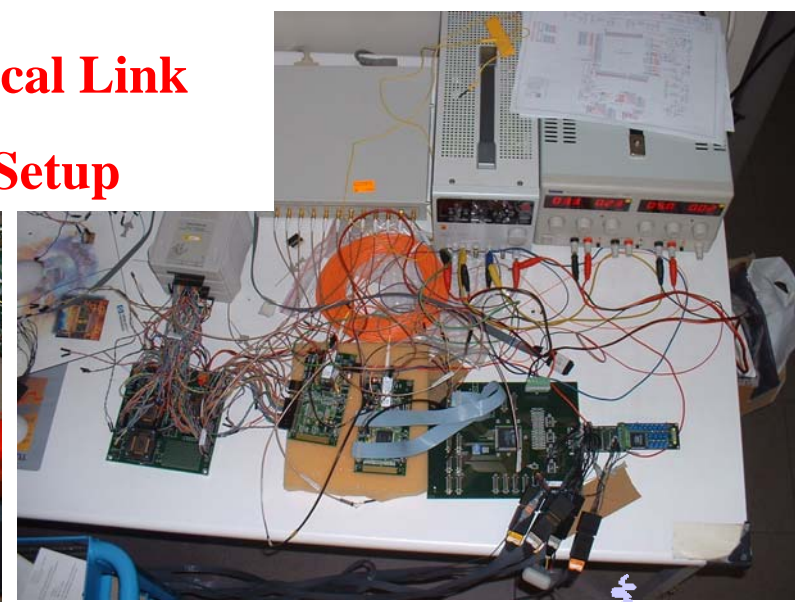
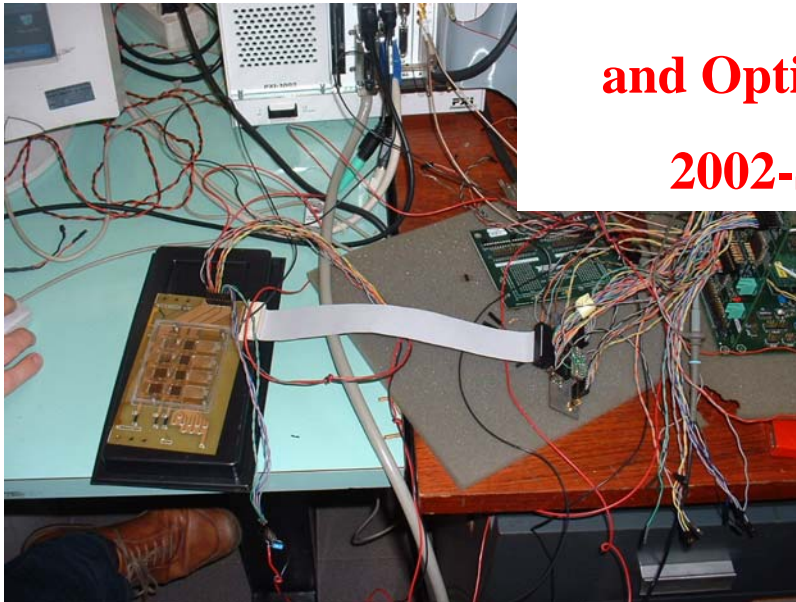
**CHAIN #3 was used at Test Beams on August 2003-2004 at CERN**



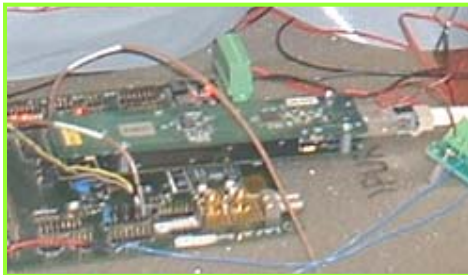
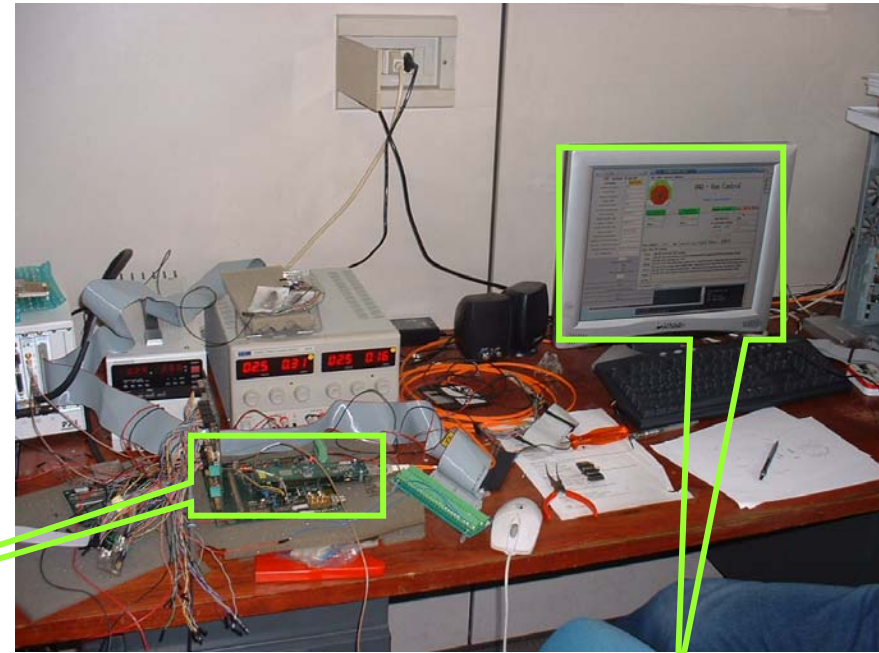
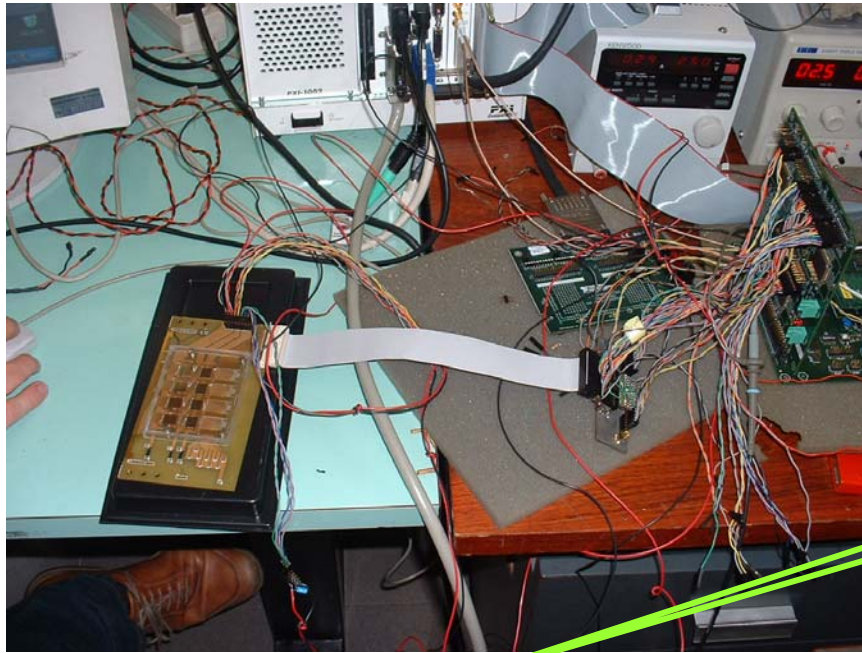
# The SDD Readout Chain in Bologna Lab



**This is with  
Serializer-Deserializer  
and Optical Link  
2002-Setup**



# Implementation of the DDL card in Bologna (2004)



**This is without Serializer-Deserializer  
and Optical Link between FEE and  
Carlos\_rx receiver card**



**Chain used for Test Beam 2004 at CERN**



# DDL monitor when the chain is under test in Bologna Lab

Number of triggers sent

The screenshot shows the DDL monitor interface. On the left, there are settings for 'device' (set to 1), 'port list' (set to 0,1), 'buffer size' (set to 10000), and 'scans to read at a time' (set to 1000). A 'STOP' button is visible. In the center, a large display shows 'Trigger read' with the value '49018' circled in red. Below this, a 'Scan Backlog' field shows '0'. The National Instruments logo is at the bottom right.

PCI-6533  
DIO-32HS

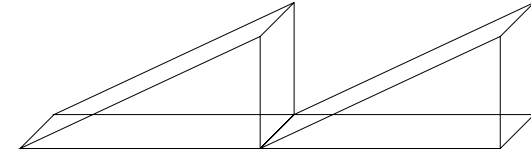
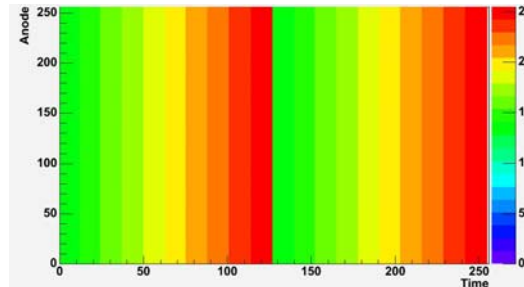
Number of events recorded

The screenshot shows the 'LDC status display' window. The 'LDC name' is 'edmVlsi7ldc'. The 'Number of events' field is circled in red and shows the value '49018'. Other fields include 'Event rate' (0), 'Number of triggers' (49018), 'Trigger rate' (0), 'Events recorded' (49020), 'Events recorded rate' (0), 'Bytes injected' (396'911'224), 'Bytes injected rate' (0), 'Bytes recorded' (396'911'224), 'Bytes recorded rate' (0), 'Bytes in buffer' (C 0% M 1% 0), 'Number of Equipments' (1), 'Readout SOR/EOR phases' (0), 'Recorder SOR/EOR phases' (0), 'edmMaskValidityRange' (firstEventId=(nbInRi), and 'GDCs nearly full'.

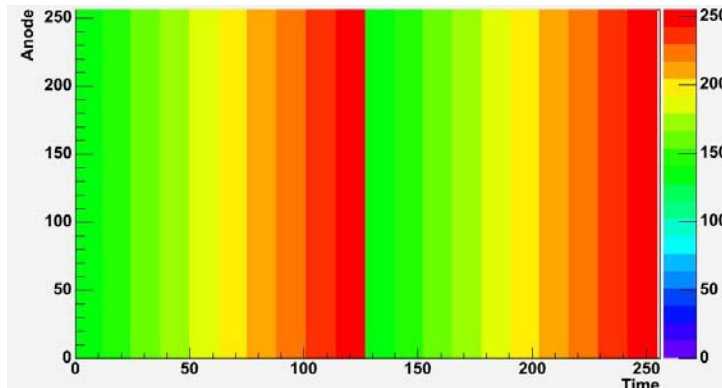
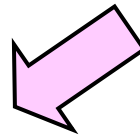


# Applying compression to the input pattern

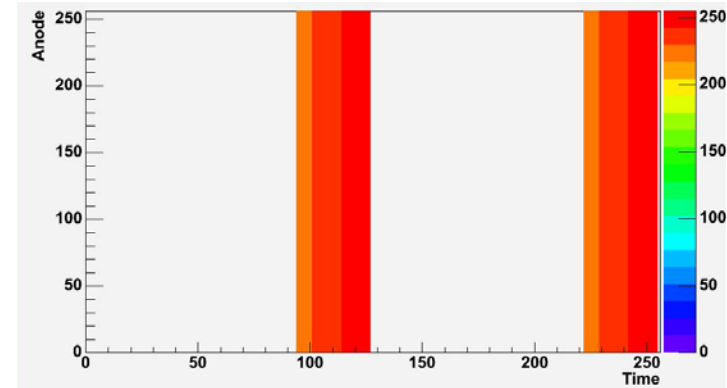
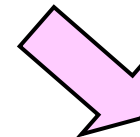
saw-tooth  
shaped artificial  
dataset



DAQ readout chain with a given setup for 2D compression



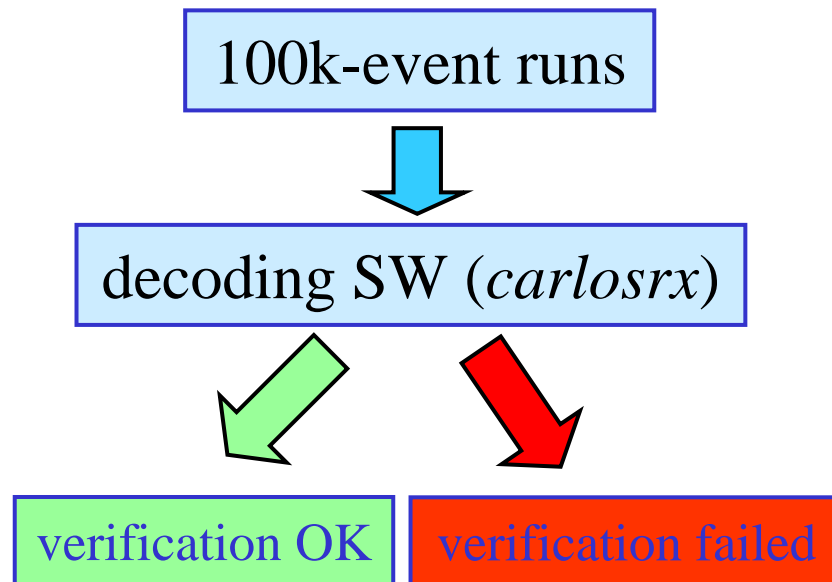
2D compression disabled



2D compression enabled



# Home-made Verification SW



## Test features:

- CARLOS programming via JTAG
  - One Looped Event: 2.5k, 16k e 64k
  - Back-pressure of CARLOSrx over CARLOS
  - Trigger frequency (up to 550 Hz)
- Upper limit (FEE) is 625 Hz

SDD

Options

Insert RAW number(press return to confirm)

Insert file number (return)

Inserisci l'anode length (invio)

Insert TH 0 (return)

Insert TH 1 (return)

Insert TL 0 (return)

Insert TL 1 (return)

Compression enable?

☐ Yes

☐ No

Insert limit number (return)

Print

Start

Controlla gli eventi uguali

IOT

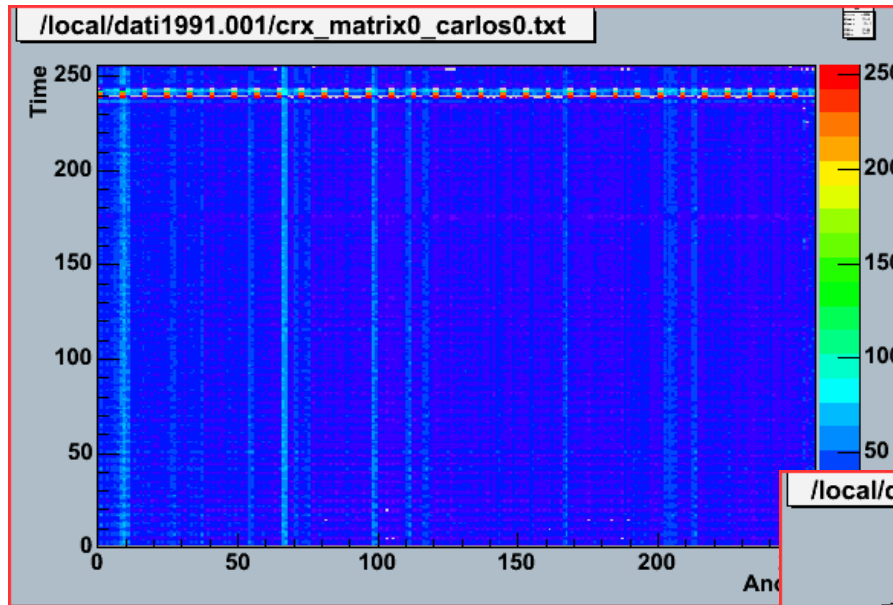
GRAPH

MEDIA

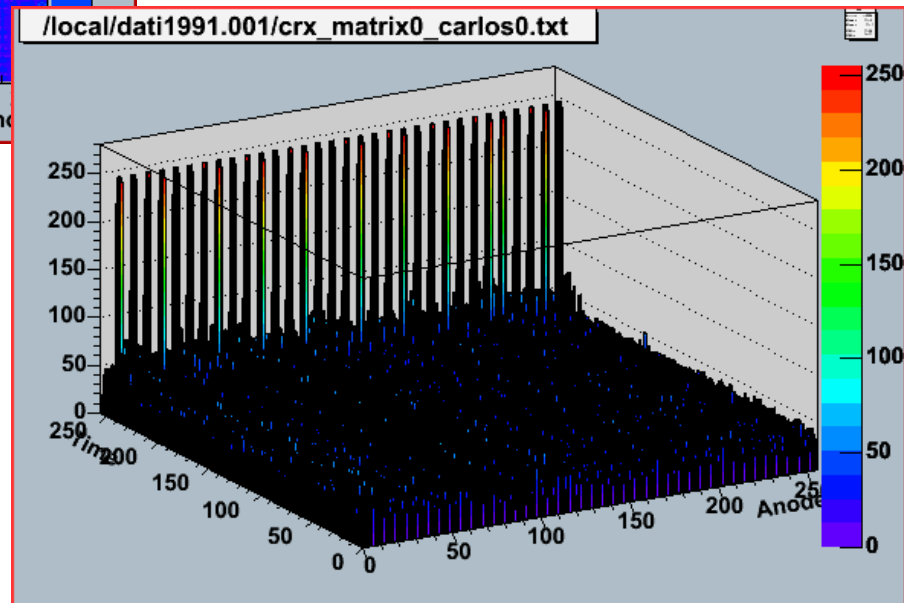
Exit



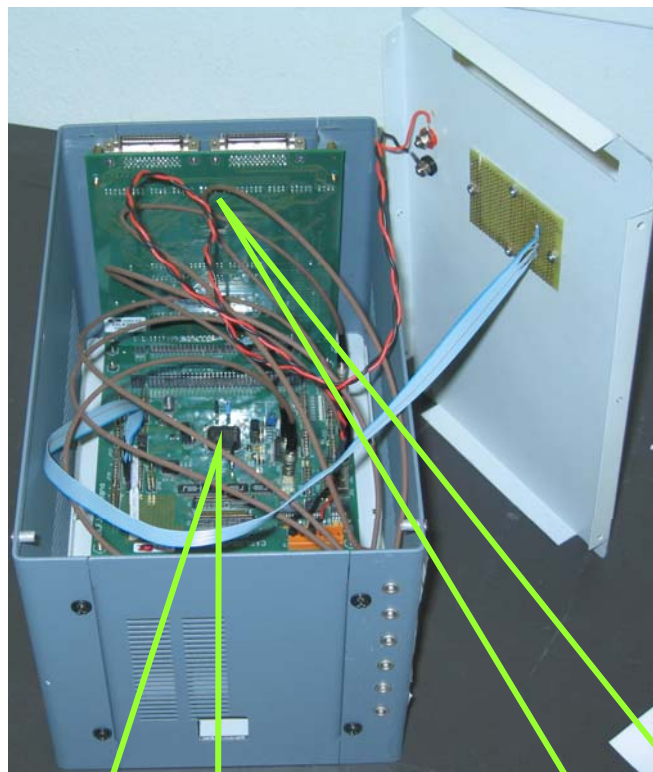
# Tests with the FEE board



Noise + test pulse  
provided by FEE without  
2D compression



## Implementation at Test-Beam on August 2004



Carlos\_rx card



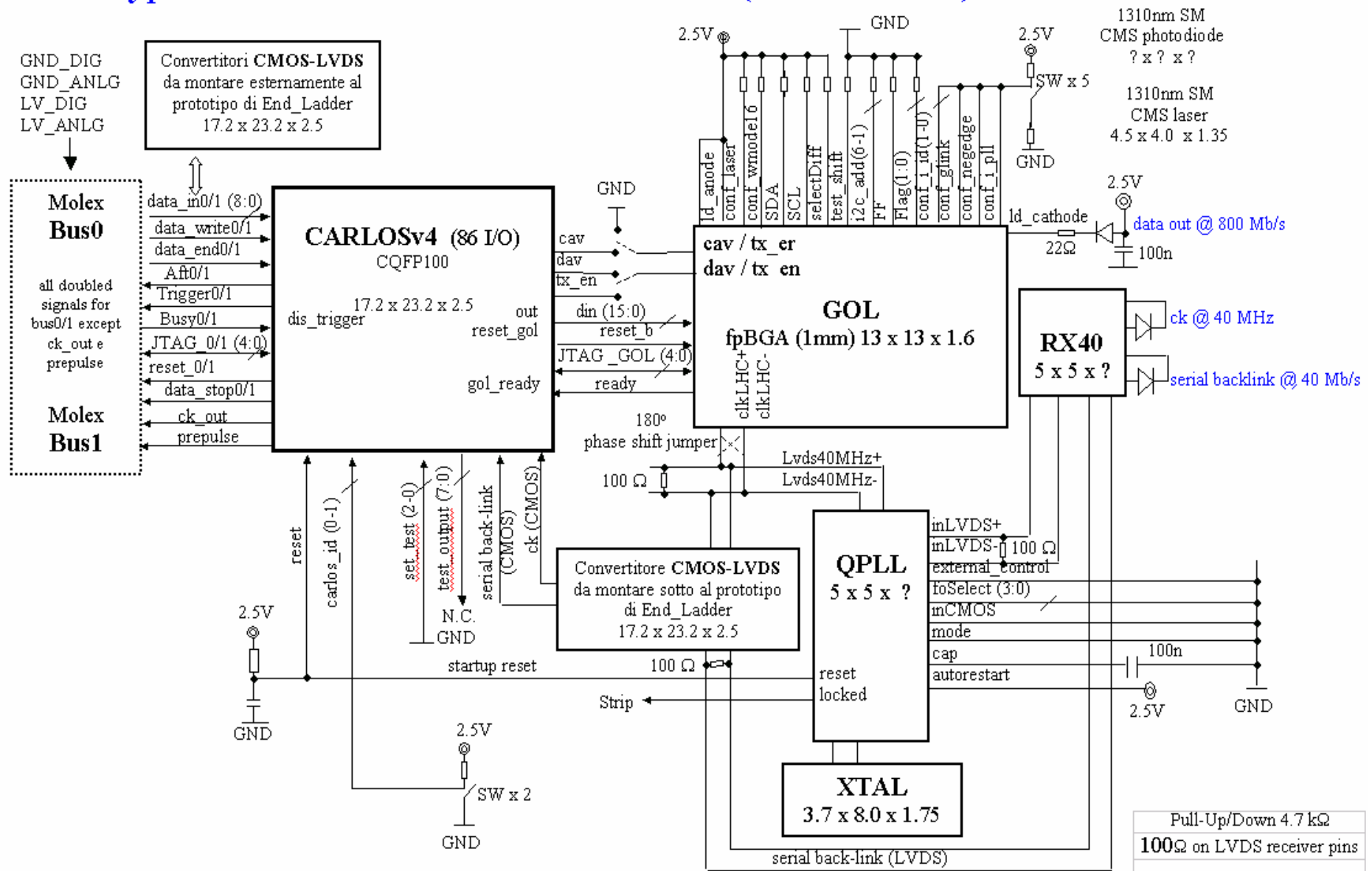
Carlos card with  
prototype chip

SDD plus FEE  
with final chips

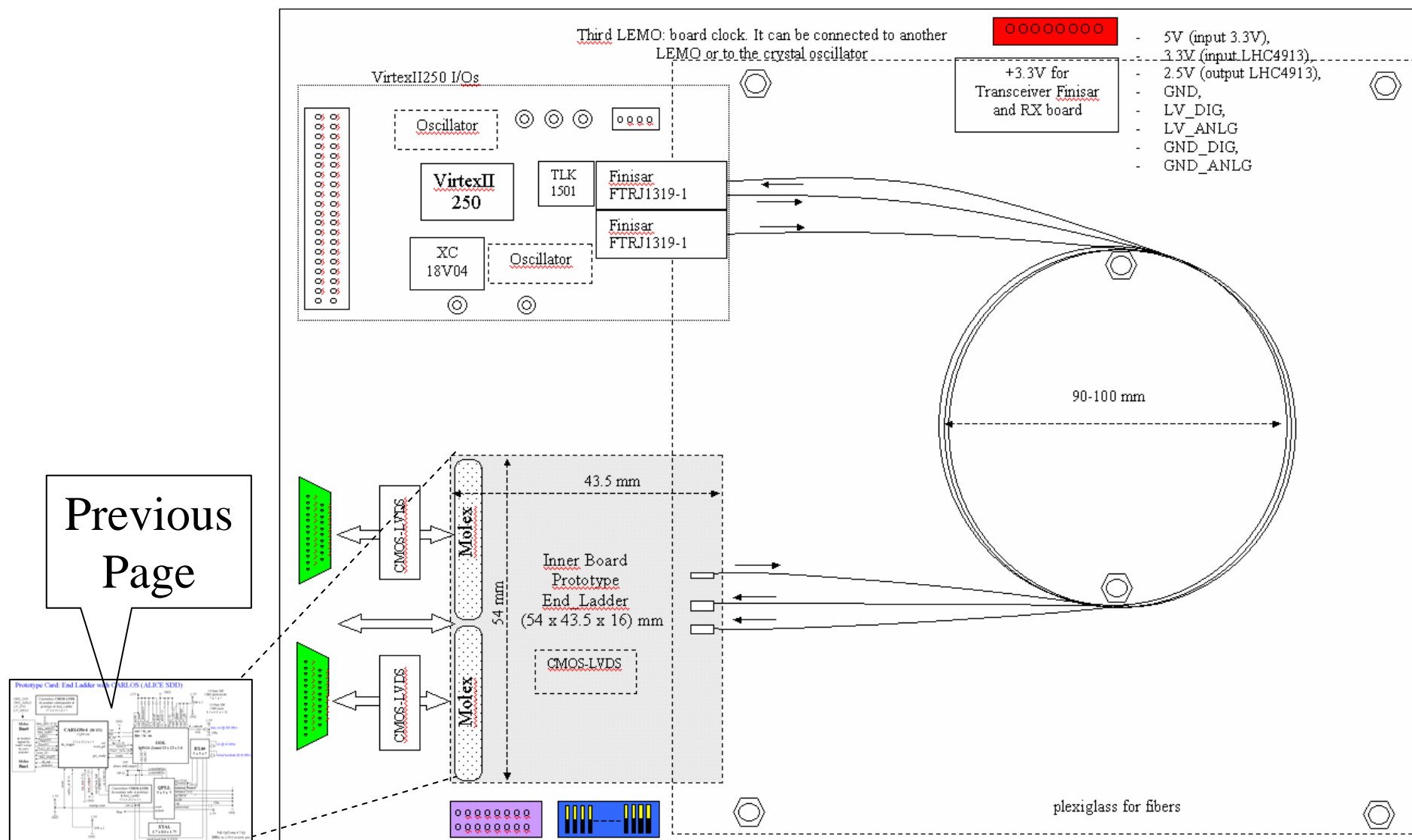
**This is without Serializer-Deserializer and Optical Link**



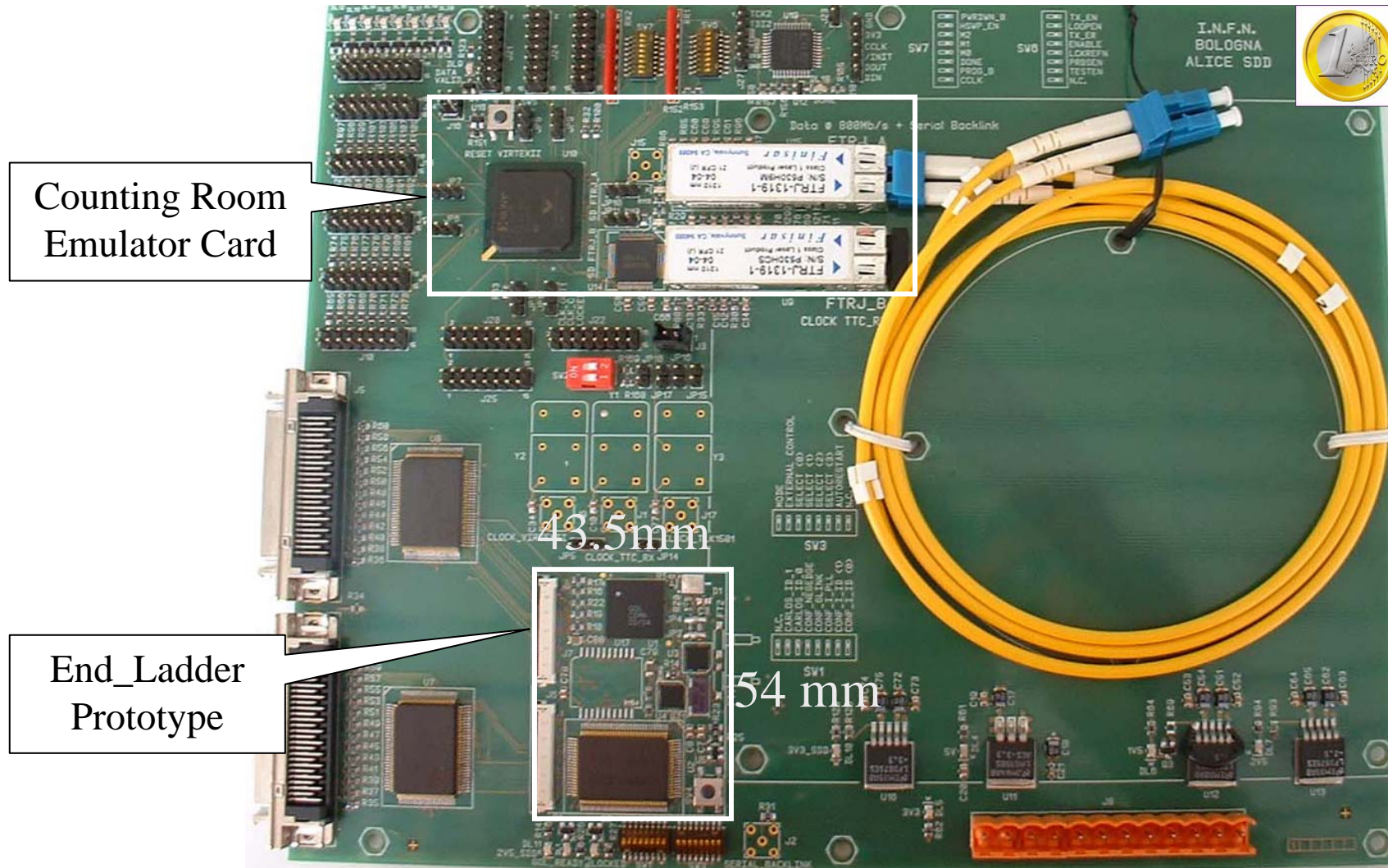
### Prototype Card: End Ladder with CARLOS (ALICE SDD)



# End-Ladder Prototype Sketch



# End-Ladder Prototype Picture



# Work Plan

- 5/04: New and last CARLOS prototype submitted on MPW13 as half-production
- 9-10/04: Test of last CARLOS prototype on 20 packaged samples
- 10/04: Second part of the production on MPW14
- 10-12/04: Test of the complete DAQ chain from FEE to DDL (prototype of the end-ladder board)
- 12/04-01/05: Packaging of the CARLOS production on BGA
- 1st\_Q/05: Test of the production (600 BGA packaged chips)  
Possible design of a more accurate and-ladder card



*End-Talk*

